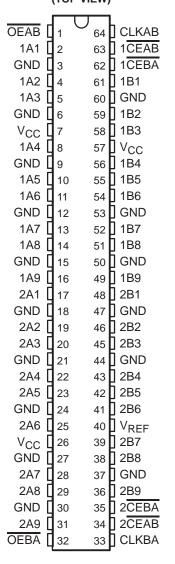
- Members of the Texas Instruments
   Widebus™ Family
- D-Type Flip-Flops With Qualified Storage Enable
- Translate Between GTL/GTL+ Signal Levels and LVTTL Logic Levels
- Support Mixed-Mode (3.3 V and 5 V) Signal Operation on A-Port and Control Inputs
- I<sub>off</sub> Supports Partial-Power-Down Mode Operation
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors on A Port
- ESD Protection Exceeds JESD 22
  - 2000-V Human-Body Model (A114-A)
  - 200-V Machine Model (A115-A)
  - 1000-V Charged-Device Model (C101)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Distributed V<sub>CC</sub> and GND-Pin Configuration Minimizes High-Speed Noise
- Package Options Include Plastic Thin Shrink Small-Outline (DGG) and Ceramic Quad Flat (HV) Packages

### description

The 'GTL16622A devices are 18-bit registered bus transceivers that provide LVTTL-to-GTL/GTL+ and GTL/GTL+-to-LVTTL signal-level translation. They are partitioned as two separate 9-bit transceivers with individual clock-enable controls and contain D-type flip-flops for temporary storage of data flowing in either direction. The devices provide an interface between cards operating at LVTTL logic levels and a backplane operating at GTL/GTL+ signal levels. Higher speed operation is a direct result of the reduced output swing (<1 V), reduced input threshold levels, and output edge control (OEC™).

## SN74GTL16622A . . . DGG PACKAGE (TOP VIEW)



The user has the flexibility of using this device at either GTL ( $V_{TT}$  = 1.2 V and  $V_{REF}$  = 0.8 V) or the preferred higher noise margin GTL+ ( $V_{TT}$  = 1.5 V and  $V_{REF}$  = 1 V) signal levels. GTL+ is the Texas Instruments derivative of the Gunning transceiver logic (GTL) JEDEC standard JESD 8-3. The B port normally operates at GTL or GTL+ signal levels, while the A-port and control inputs are compatible with LVTTL logic levels and are 5-V tolerant.  $V_{REF}$  is the reference input voltage for the B port.



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### description (continued)

Data flow in each direction is controlled by the output-enable ( $\overline{OEAB}$  and  $\overline{OEBA}$ ) and clock (CLKAB and CLKBA) inputs. The clock-enable ( $\overline{CEAB}$  and  $\overline{CEBA}$ ) inputs are designed to control each 9-bit transceiver independently, which makes the device more versatile.

For A-to-B data flow, the device operates on the low-to-high transition of CLKAB if CEAB is low. When OEAB is low, the outputs are active. When OEAB is high, the outputs are in the high-impedance state. Data flow for B to A is similar to that of A to B, but uses OEBA, CLKBA, and CEBA.

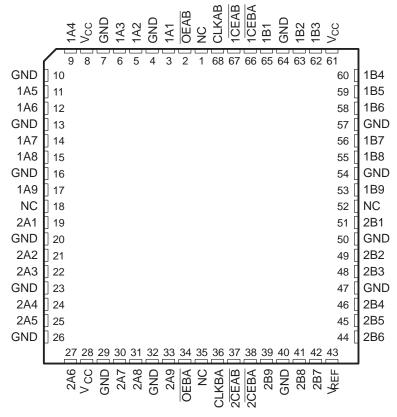
These devices are fully specified for partial-power-down applications using I<sub>off</sub>. The I<sub>off</sub> circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

Active bus-hold circuitry holds unused or undriven LVTTL inputs at a valid logic state. Use of pullup or pulldown resistors with the bus-hold circuitry is not recommended.

To ensure the high-impedance state during power up or power down,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54GTL16622A is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to  $125^{\circ}$ C. The SN74GTL16622A is characterized for operation from  $-40^{\circ}$ C to  $85^{\circ}$ C.

# SN54GTL16622A . . . HV PACKAGE (TOP VIEW)



NC - No internal connection



## SN54GTL16622A, SN74GTL16622A 18-BIT LVTTL-TO-GTL/GTL+ BUS TRANSCEIVERS

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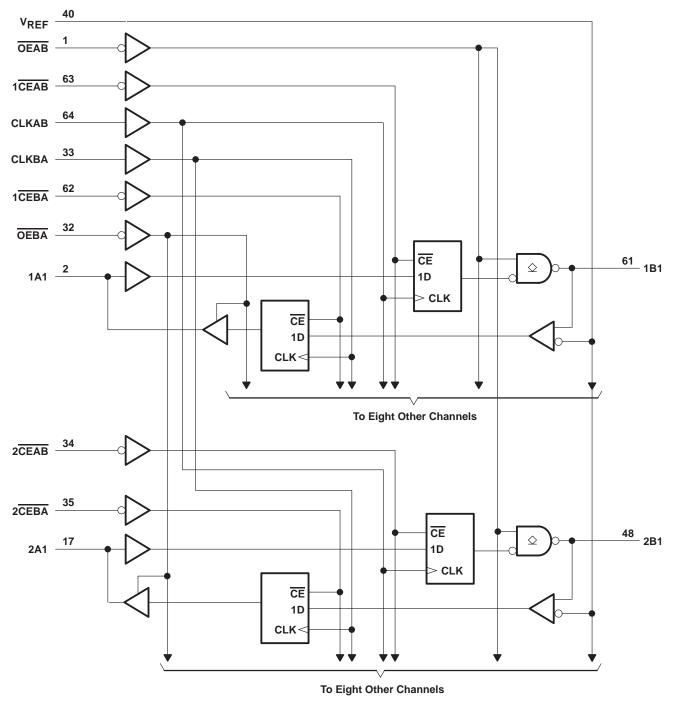
#### **FUNCTION TABLE**†

	INP	UTS		OUTPUT	MODE
CEAB	OEAB	CLKAB	Α	В	MODE
Х	Н	Χ	Χ	Z	Isolation
Н	L	Х	Х	в <sub>0</sub> ‡	Latched storage of A data
Х	L	H or L	Χ	<sub>В0</sub> ‡ В <sub>0</sub> ‡	Latched Storage of A data
L	L	<b>↑</b>	L	L	Clasked storage of A data
L	L	$\uparrow$	Н	Н	Clocked storage of A data

<sup>†</sup> A-to-B data flow is shown. B-to-A data flow is similar, but uses OEBA, CLKBA, and CEBA.

<sup>&</sup>lt;sup>‡</sup>Output level before the indicated steady-state input conditions are established

### logic diagram (positive logic)



Pin numbers shown are for the DGG package.



### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage range, V <sub>CC</sub>	–0.5 V to 4.6 V
Input voltage range, V <sub>I</sub> (see Note 1): A-port and control inputs	–0.5 V to 6.5 V
B port and V <sub>REF</sub>	–0.5 V to 4.6 V
Voltage range applied to any output in the high or power-off state, VO	
(see Note 1): A port	–0.5 V to 6.5 V
B port	–0.5 V to 4.6 V
Current into any output in the low state, IO: A port	
B port	100 mA
Current into any A-port output in the high state, I <sub>O</sub> (see Note 2)	48 mA
Continuous current through each V <sub>CC</sub> or GND	±100 mA
Input clamp current, $I_{ K }(V_1 < 0)$	–50 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0)	
Package thermal impedance, θ <sub>JA</sub> (see Note 3)	55°C/W
Storage temperature range, T <sub>stg</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
  - 2. This current flows only when the output is in the high state and  $V_O > V_{CC}$ .
  - 3. The package thermal impedance is calculated in accordance with JESD 51.

### recommended operating conditions (see Notes 4 through 6)

			SN	SN54GTL16622A SN74GTL16622A		SN74GTL16622A			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNII
Vcc	Supply voltage		3.15	3.3	3.45	3.15	3.3	3.45	V
\/	Termination	GTL	1.14	1.2	1.26	1.14	1.2	1.26	V
VTT	voltage	GTL+	1.35	1.5	1.65	1.35	1.5	1.65	V
\/	Cumply valtage	GTL	0.74	0.8	0.87	0.74	0.8	0.87	V
VREF	Supply voltage	GTL+	0.87	1	1.1	0.87	1	1.1	V
V.	Input voltage	B port		j	\$ VTT			VTT	V
VI		Except B port		Z.	5.5			5.5	V
\/	High-level	B port	V <sub>REF</sub> +50 m <sup>v</sup>	V 92		V <sub>REF</sub> +50 mV			V
VIH	input voltage	Except B port	2	5		2			V
\/	Low-level	B port		20	VREF-50 mV			V <sub>REF</sub> -50 mV	V
VIL	input voltage	Except B port		02	0.8			0.8	V
lικ	Input clamp current		4	2	-18			-18	mA
ЮН	High-level output current	A port			-24			-24	mA
1	Low-level	A port			24			24	Δ
lOL	output current	B port			50			50	mA
TA	Operating free-air to	emperature	<b>–</b> 55		125	-40		85	°C

NOTES: 4. All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

- 5. Normal connection sequence is GND first and V<sub>CC</sub> = 3.3 V, I/O, control inputs, V<sub>TT</sub> and V<sub>REF</sub> (any order) last.
- V<sub>TT</sub> and R<sub>TT</sub> can be adjusted to accommodate backplane impedances as long as they do not exceed the DC absolute I<sub>OL</sub> ratings.
   Similarly, V<sub>REF</sub> can be adjusted to optimize noise margins, but normally is 2/3 V<sub>TT</sub>.



### SN54GTL16622A, SN74GTL16622A 18-BIT LVTTL-TO-GTL/GTL+ BUS TRANSCEIVERS

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# electrical characteristics over recommended operating free-air temperature range for GTL/GTL+ (unless otherwise noted)

DAI	DAMETER	TEST 04	PAIDITIONS	SN540	GTL1662	2A	SN740	STL1662	2A	
PAI	RAMETER	l lesi co	ONDITIONS	MIN	TYP <sup>†</sup>	MAX	MIN	TYP <sup>†</sup>	MAX	UNIT
۷ıK		$V_{CC} = 3.15 \text{ V},$	I <sub>I</sub> = -18 mA			-1.2			-1.2	V
		V <sub>CC</sub> = 3.15 V to 3.45	5 V, I <sub>OH</sub> = -100 μA	V <sub>CC</sub> -0.2			V <sub>CC</sub> -0.2			
Vон	A port	V <sub>CC</sub> = 3.15 V	$I_{OH} = -12 \text{ mA}$	2.4			2.4			V
		vCC = 3.13 v	$I_{OH} = -24 \text{ mA}$	2			2		0.2 0.4 0.5 0.2 0.4 0.55 ±5 ±5 ±10 100  ±500 60 60 500	
		$V_{CC} = 3.15 \text{ V to } 3.45$	5 V, I <sub>OL</sub> = 100 μA			0.2			0.2	
	A port	V <sub>CC</sub> = 3.15 V	I <sub>OL</sub> = 12 mA			0.4			0.4	
		VCC = 3.13 V	I <sub>OL</sub> = 24 mA			0.5			0.5	
VOL		$V_{CC} = 3.15 \text{ V to } 3.45$	$5 \text{ V, I}_{OL} = 100 \mu\text{A}$			0.2			0.2	V
	B nort		I <sub>OL</sub> = 10 mA			0.2			0.2	
	B port	V <sub>CC</sub> = 3.15 V	$I_{OL} = 40 \text{ mA}$			0.4			0.4	
		0.55								
	B port	V <sub>CC</sub> = 3.45 V	V <sub>I</sub> = V <sub>TT</sub> or GND		±:	±5		±5		
II	A-port and	V = = - 2.45 V	V <sub>I</sub> = V <sub>CC</sub> or GND	±5				±5		
	control inputs	VCC = 3.45 V	V <sub>I</sub> = 5.5 V or GND		13.	±20			±5 ±5 ±20	
l <sub>off</sub>		$V_{CC} = 0$ ,	$V_{I}$ or $V_{O} = 0$ to 5.5 V		Q	100			100	μΑ
		V <sub>CC</sub> = 3.15 V	V <sub>I</sub> = 0.8 V	75		75				
I <sub>I</sub> (hold)	A port	vCC = 3.13 v	V <sub>I</sub> = 2 V	-75	3		-75			μΑ
		$V_{CC} = 3.45 V^{\ddagger}$ ,	$V_I = 0.8 \text{ V to 2 V}$	2000		±500			±500	
I <sub>OZ</sub> §	A port	$V_{CC} = 3.45 \text{ V},$	$V_O = V_{CC}$ or GND			±10			±10	μΑ
lozh	B port	$V_{CC} = 3.45 \text{ V},$	V <sub>O</sub> = 1.5 V			10			10	μΑ
		V <sub>CC</sub> = 3.45 V,	Outputs high		60				60	
ICC	A or B port	$I_O = 0$ ,	Outputs low			60			60	mA
		$V_I = V_{CC}$ or GND	Outputs disabled			60			60	
ΔI <sub>CC</sub> ¶		V <sub>CC</sub> = 3.45 V, A-port or control inpu One input at V <sub>CC</sub> – 0				500			500	μΑ
Ci	Control inputs	V <sub>I</sub> = 3.15 V or 0			2.5	3		2.5	3	pF
0.	A port	V- 245 V - 2			6	8.5		6	8	
Cio	B port	$V_O = 3.15 \text{ V or } 0$			7	9.5		6.5	8.5	pF

 $<sup>\</sup>dagger$  All typical values are at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C.

<sup>‡</sup> This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

 $<sup>\</sup>mbox{\colored}$  For I/O ports, the parameter  $\mbox{\colored}_{\mbox{OZ}}$  includes the input leakage current.

This is the increase in supply current for each input that is at the specified TTL voltage level rather than VCC or GND.

# timing requirements over recommended ranges of supply voltage and operating free-air temperature for GTL (unless otherwise noted)

				16622A	SN74GTL	UNIT		
			MIN	MAX	MIN	MAX	UNIT	
fclock	Clock frequency			200		200	MHz	
t <sub>W</sub>	Pulse duration, CLK high or low		2.5	Á	2.5		ns	
	Cotum time	Data before CLK↑	2.5	200	2.1			
<sup>L</sup> SU	su Setup time	CE before CLK↑	3.5	7/-	3.3		ns	
+.	Hold time	Data after CLK↑	0.3		0.3		no	
t <sub>h</sub>	noid time	CE after CLK↑	0.3		0		ns	

# switching characteristics over recommended ranges of supply voltage and operating free-air temperature for GTL (see Figure 1)

DADAMETED	FROM	ТО	SN54	SN54GTL16622A			SN74GTL16622A		
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP <sup>†</sup>	MAX	MIN	TYP <sup>†</sup>	MAX	UNIT
f <sub>max</sub>			200			200			MHz
<sup>t</sup> PLH	CLKAB	В	2.4		5.7	2.5		5.5	no
<sup>t</sup> PHL	CLNAB	Б	2.1		5.7	2.2		5.5	ns
<sup>t</sup> dis	OFAR	В	1.6		5	1.7		4.8	no
t <sub>en</sub>	OEAB	ь	2.1	4	5.5	2.2		5.2	ns
Slew rate	Both transiti	ons (B port)		0.5			0.5		V/ns
t <sub>r</sub>	Transition time, B or	utputs (0.6 V to 1 V)	0.5	Ş	2.3	0.6		2.2	ns
t <sub>f</sub>	Transition time, B or	utputs (1 V to 0.6 V)	0.3	9	1.7	0.4		1.5	ns
<sup>t</sup> PLH	CLKBA	А	1.9	-	5.5	2.1		5.3	
<sup>t</sup> PHL	CLNDA		1.8		5.3	2.1		5	ns
t <sub>en</sub>	OFDA	۸	1.6		5.3	1.7		5	no
<sup>t</sup> dis	OEBA	A	2		5.8	2.3		5.5	ns

 $<sup>\</sup>uparrow$  All typical values are at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C.

### SN54GTL16622A, SN74GTL16622A 18-BIT LVTTL-TO-GTL/GTL+ BUS TRANSCEIVERS

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# timing requirements over recommended ranges of supply voltage and operating free-air temperature for GTL+ (unless otherwise noted)

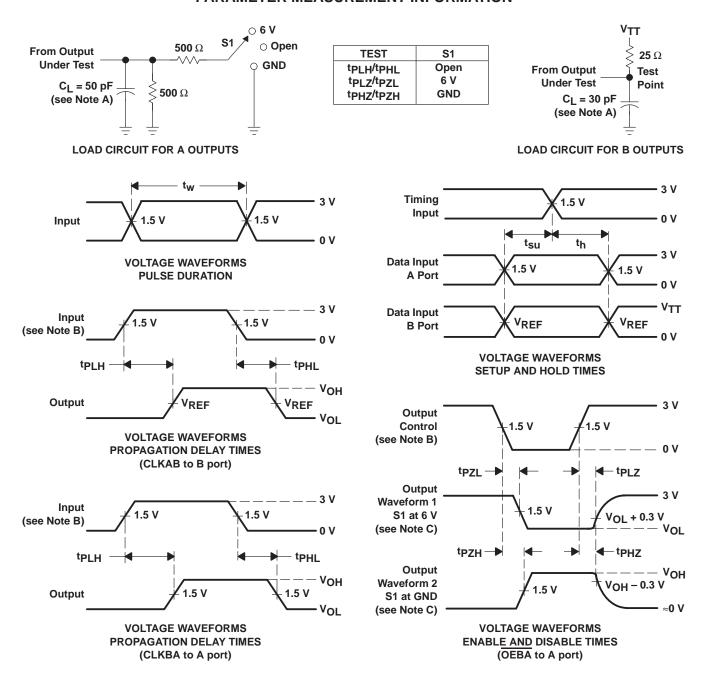
			SN54GTL	16622A	SN74GTL1	16622A	UNIT
			MIN	MAX	MIN	MAX	UNIT
fclock	Clock frequency			200		200	MHz
t <sub>W</sub>	Pulse duration, CLK high or low		2.5	Á	2.5		ns
	Catum time	Data before CLK↑	2.5	L'II	2.4		
tsu	Su Setup time	CE before CLK↑	3.4		3.2		ns
+.	Hold time	Data after CLK↑	0.3		0.2		no
t <sub>h</sub>	noia time	CE after CLK↑	0.1		0		ns

# switching characteristics over recommended ranges of supply voltage and operating free-air temperature for GTL+ (see Figure 1)

PARAMETER	FROM TO		SN5	SN54GTL16622A			SN74GTL16622A			
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP <sup>†</sup>	MAX	MIN	TYP	MAX	UNIT	
f <sub>max</sub>			200			200			MHz	
<sup>t</sup> PLH	CLKAB	В	2.5		5.8	2.6	4	5.6	ns	
<sup>t</sup> PHL	CLINAD	Ь	2.2		6.1	2.3	4	5.7	115	
<sup>t</sup> PLH	OEAB	В	2.3		5.5	2.4	3.8	5.2	ns	
<sup>t</sup> PHL	OEAD	ט	1.7	K	5.3	1.8	3.4	5	115	
Slew rate	Both transiti	ons (B port)		0.5			0.5		V/ns	
t <sub>r</sub>	Transition time, B ou	tputs (0.6 V to 1.3 V)	0.9	2	2.8	1	1.6	2.7	ns	
t <sub>f</sub>	Transition time, B ou	tputs (1.3 V to 0.6 V)	0.4	Ş <sup>2</sup>	3.7	0.5	1.1	3.2	ns	
<sup>t</sup> PLH	CLKBA	А	1.9		5.5	2	3.8	5.3	ns	
<sup>t</sup> PHL	CLRBA		1.8		5.3	1.9	3.6	5	115	
t <sub>en</sub>	OEBA	А	1.8		5.3	1.9	3.6	5	ns	
<sup>t</sup> dis	] OEBA	A	2		5.8	2.1	4	5.5	115	

<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{CC} = 3.3 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

#### PARAMETER MEASUREMENT INFORMATION



- NOTES: A.  $C_L$  includes probe and jig capacitance.
  - B. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50 \Omega$ ,  $t_r \leq 2.5$  ns,  $t_f \leq 2.5$  ns.
  - C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  - D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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